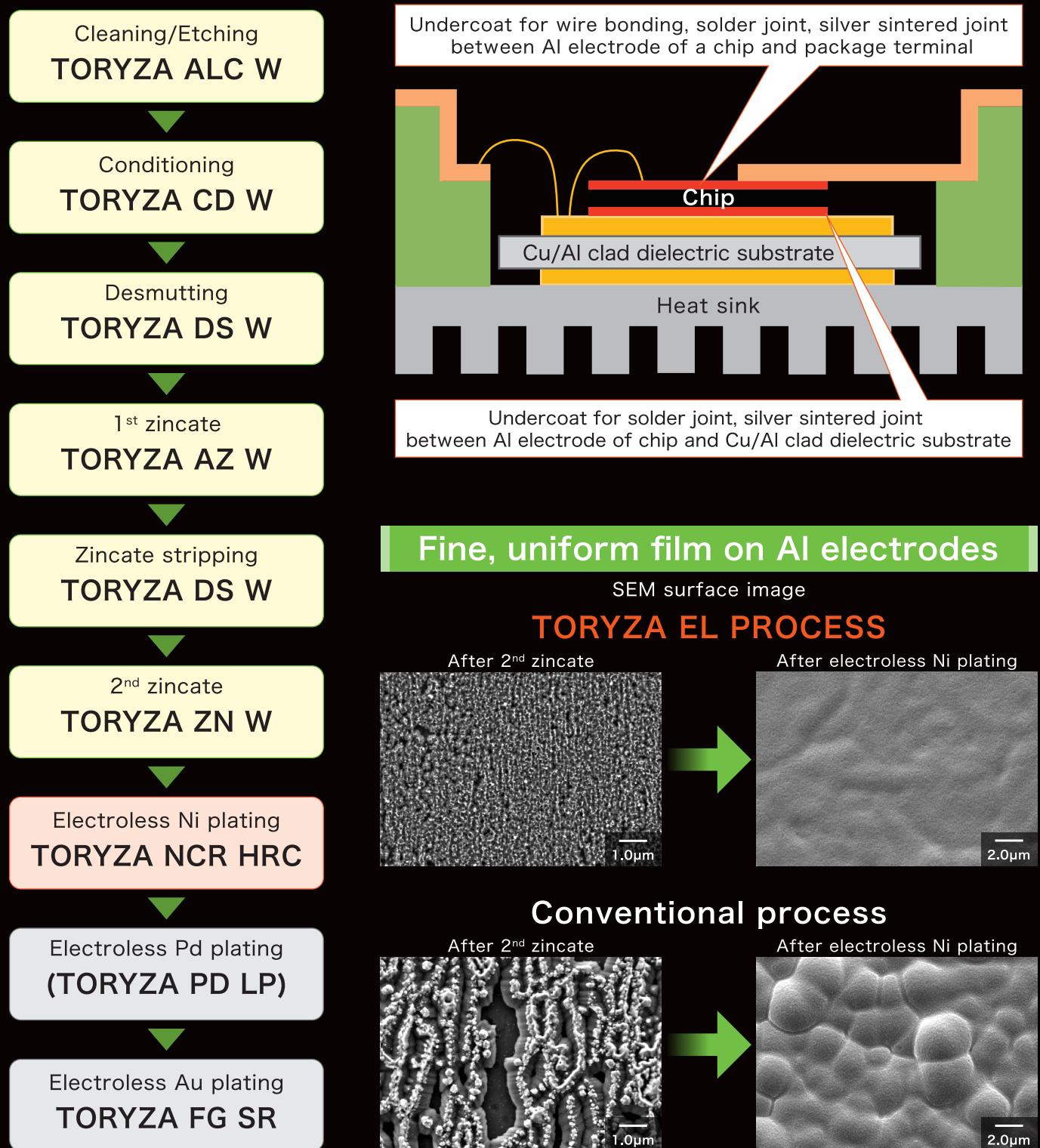


## UBM formation on aluminum electrode on wafer

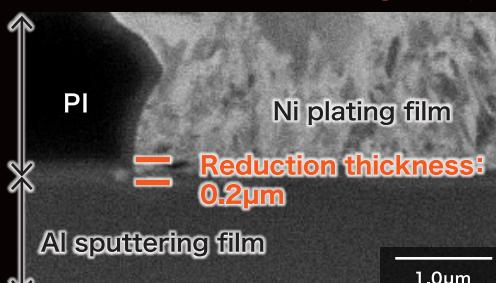
# TORYZA EL PROCESS

- Zincate films are densely formed to achieve smooth plating films
- Pre-treatment process: Reduce etching amount of Al sputtering films, prevent local corrosion
- Electroless Ni plating films are suitable for high temperature joint and use

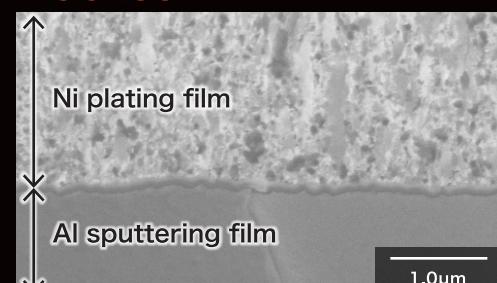


## Prevent local corrosion of Al sputtering layer

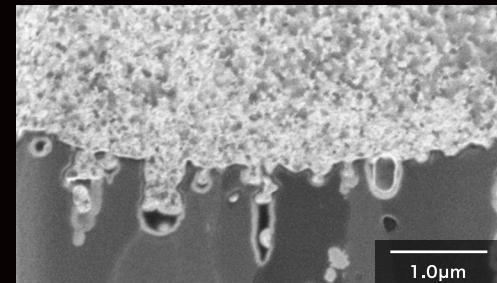
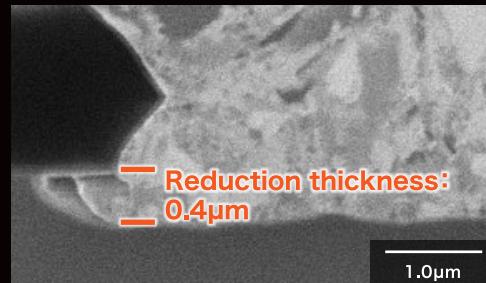
SIM cross section image after electroless Ni plating



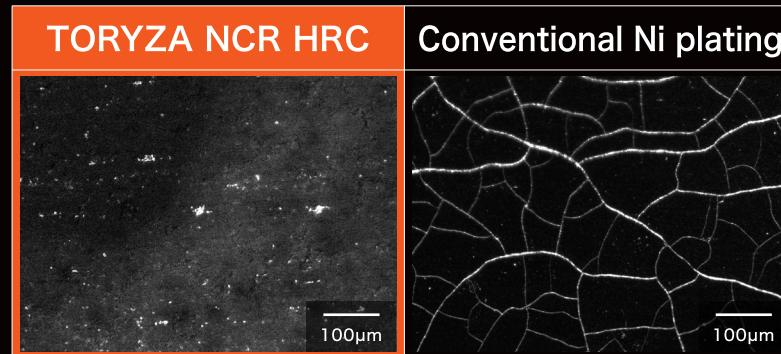
Conventional process



Conventional process



## Electroless Ni plating film applicable to high-temperature jointing



Heat treatment:  
400°C 30min

Indentation test by Erichsen tester (Ni thickness: 3μm, indentation width: 0.5mm)

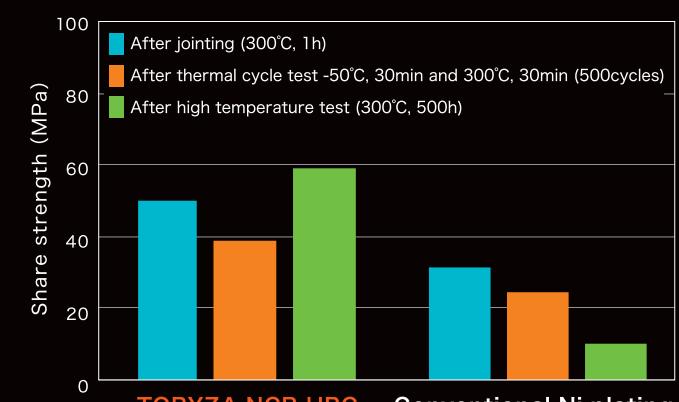
## Prevent cracks after 400°C heat treatment

## Electroless Ni plating film applicable to use under high-temperature environment

Crack occurrence comparison of electroless Ni plating film

Electroless Ni plating film	Crack occurrence		
	After jointing	After thermal cycle	After high temperature test
TORYZA NCR HRC	No	No	No
Conventional Ni plating	No	Occur	Occur

Presented by SANKEN, Osaka University Flexible 3D JISSO Collaborative Research institute  
SiC Chip: Ti sputtering on SiC chip, and form Ag sputtering layer  
Jointing condition: Electroless Ni plating (7μm thickness) on DBA substrate and sintering SiC chip on DBA substrate with Ag paste  
Adding 1MPa pressure, 300°C, 1h



Share strength after silver sintered joint